

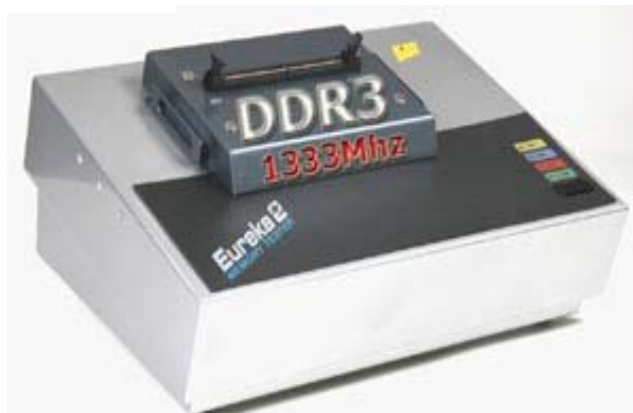
Eureka2 DDR3 1333Mhz

NEW! Innovative Memory Tester

CST Inc, a leading worldwide manufacturer of memory tester and automatic Handler is proud to introduce the new Eureka-II Memory Tester, specifically designed for high volume memory distributor, memory module manufacturers, and memory repair service centers

The Eureka-II DDR3 Tester support the standard 240pin DIMM socket for testing the latest PC3-6400,PC3- 8500,PC3-10666, DDR3 memory modules at "Real Bus Speed" and "Real Cycle Time".

The Eureka-II DDR3 tester is designed and built with a flexible architecture which can support testing DDR, DDR2, DDR3 DIMM memory module with a change of optional Test Adapters.



Eureka2 DDR3 Feature

Auto Identify:

- Memory Type: Registered or Unbuffered
- Memory Configuration
- Memory Size
- Memory Frequency
- Memory Latency
- ECC or Non-ECC

Real Bus Speed Testing

- Real Cycle Time
- Super Fast Test time(1GB under 20secs)

Effective Test Algorithm

- Quick test, checks for assembly faults
- 20 Types of March test Pattern , to check for functional failures
- Programming and checking SPD
- **Fault Focusing pinpoint to faulty BGA chip**
- **DC Parametric/Leakage Test**

Advanced Feature.

- Intuitive User PC Interface Software
- User configurable Test Pattern
- Auto-Speed Sorting Tool
- SHMOO-Plot and Error Mapping Tool
- Auto Timing Setup
- Current measurement
- Programmable DDR3 AC Parameters

Ez Upgrading

- Firmware upgrade via internet
- Support RoboFlex2/RoboFlex3 Handler
- Interface with PC software via USB Port

Eureka2 DDR3 Technical Specification

Clock Frequency	: 400, 533, & 667 Mhz selectable
Data-rate	: 800,1066 & 1333 Mhz
Address depth	: 4 Giga-word (16 Row x 16 Col)
Data width	: Expandable 64 & 72 bit
Voltage range	: 1.3,1.4.1.5.1.6,1.7,1.8,1.9 to 2.0V
ICC measurement	: IDD 0 – IDD7
CAS Read Latency	: 5,6,7,8,9 & 10 Clocks
Trcd & Trp Adjustment	: 5,6,7,8,9 & 10 Clocks
Burst Length	: 4 & 8
Cas Write Latency	: 5,6,7 & 8 clock
Mirror-Mode	: Automatic
Dynamic ODT Adjut	: 40,60, 120 ohm and Auto
ZQ Adjustment	: Auto Calibration
Refresh Cycle	: Auto / Self Refresh
DC Parametric Testing	: +/- 1 uA to 5mA
DC Test Pattern	: Walk Data , Walk Address , DQS, DQM, CKE, CS , and BA test
AC Test Pattern	: Mat-S, March-C, March-X, March Y(23 Type March Pattern)
SPD Programming	: Read/Write & Editable Byte 0 – 255 Reversible SPD Write Protect

General Specification

Single Site	
DDR3 Test Adapter	: 240 Pin DDR3 DIMM (Standard) : 204 Pin DDR3 SODIMM (Optional) : 78/96 Ball BGA Chip Adapter
Power Adapter	: Input 100 /250 Vac, 50 /60Hz ATX
Operating Temperature	: 15 ~110 Degree F
Host PC (Not included)	: AMD or Intel P4 via USB interface
Operating System	: Microsoft Win98/2000, XP,Vista

SIMMTESTER.COM

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